INTEGRATED CIRCUITS



Product specification IC23 Data Handbook 1995 Sep 22



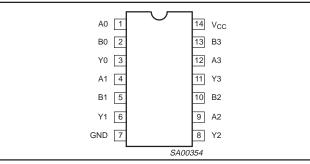
Philips Semiconductors

74ABT32

QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS $T_{amb} = 25^{\circ}C;$ GND = 0V	TYPICAL	UNIT
t _{PLH} t _{PHL}	Propagation delay An, Bn to Yn	C _L = 50pF; V _{CC} = 5V	2.3 1.9	ns
t _{OSLH} t _{OSHL}	Output to Output skew	vCC = 3 v	0.4	ns
C _{IN}	Input capacitance	$V_I = 0V \text{ or } V_{CC}$	3	pF
I _{CC}	Total supply current	Outputs disabled; $V_{CC} = 5.5V$	50	μΑ

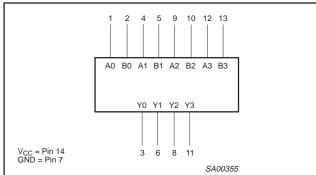
PIN CONFIGURATION



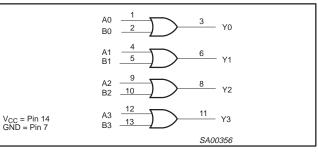
PIN DESCRIPTION

PIN NUMBER	SYMBOL	NAME AND FUNCTION
1, 2, 4, 5, 9, 10, 12, 13	An, Bn	Data inputs
3, 6, 8, 11	Yn	Data outputs
7	GND	Ground (0V)
14	V _{CC}	Positive supply voltage

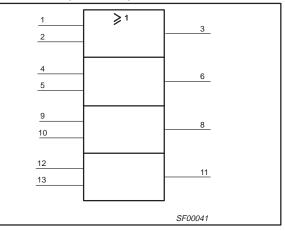
LOGIC SYMBOL



LOGIC DIAGRAM



LOGIC SYMBOL (IEEE/IEC)



FUNCTION TABLE

INP	JTS	OUTPUT
An	Bn	Yn
L	L	L
L	Н	Н
Н	L	Н
Н	Н	Н

NOTES:

H = High voltage level L = Low voltage level

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
14-Pin Plastic DIP	-40°C to +85°C	74ABT32 N	74ABT32 N	SOT27-1
14-Pin plastic SO	-40°C to +85°C	74ABT32 D	74ABT32 D	SOT108-1
14-Pin Plastic SSOP Type II	-40°C to +85°C	74ABT32 DB	74ABT32 DB	SOT337-1
14-Pin Plastic TSSOP Type I	-40°C to +85°C	74ABT32 PW	74ABT32PW DH	SOT402-1

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ABSOLUTE MAXIMUM RATINGS^{1, 2}

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +7.0	V
I _{IK}	DC input diode current	V ₁ < 0	-18	mA
VI	DC input voltage ³		-1.2 to +7.0	V
I _{OK}	DC output diode current	V _O < 0	-50	mA
V _{OUT}	DC output voltage ³	output in Off or High state	-0.5 to +5.5	V
I _{OUT}	DC output current	output in Low state	40	mA
T _{stg}	Storage temperature range		-65 to 150	°C

NOTES:

 Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

 The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.

3. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIM	UNIT	
STMBOL	TANAMETER	MIN	MAX	UNIT
V _{CC}	DC supply voltage	4.5	5.5	V
VI	Input voltage	0	V _{CC}	V
V _{IH}	High-level input voltage	2.0		V
V _{IL}	Low-level input voltage		0.8	V
I _{OH}	High-level output current		-15	mA
I _{OL}	Low-level output current		20	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0	10	ns/V
T _{amb}	Operating free-air temperature range	-40	+85	°C

DC ELECTRICAL CHARACTERISTICS

					LIMITS	LIMITS					
SYMBOL	PARAMETER	TEST CONDITIONS		T _{amb} = +25°C			T _{amb} = −40°C to +85°C				
			MIN	TYP	MAX	MIN	MAX	1			
V _{IK}	Input clamp voltage	$V_{CC} = 4.5 V; I_{IK} = -18 mA$		-0.9	-1.2		-1.2	V			
V _{OH}	High-level output voltage	V_{CC} = 4.5V; I_{OH} = -15mA; V_I = V_{IL} or V_{IH}	2.5	2.9		2.5		V			
V _{OL}	Low-level output voltage	V_{CC} = 4.5V; I_{OL} = 20mA; V_I = V_{IL} or V_{IH}		0.35	0.5		0.5	V			
l _l	Input leakage current	$V_{CC} = 5.5V; V_{I} = GND \text{ or } 5.5V$		±0.01	±1.0		±1.0	μA			
I _{OFF}	Power-off leakage current	V_{CC} = 0.0V; V_O or $V_1 \le 4.5V$		±5.0	±100		±100	μA			
I _{CEX}	Output High leakage current	V_{CC} = 5.5V; V_{O} = 5.5V; V_{I} = GND or V_{CC}		5.0	50		50	μA			
Ι _Ο	Output current ¹	$V_{CC} = 5.5 V; V_O = 2.5 V$	-50	-75	-180	-50	-180	mA			
I _{CC}	Quiescent supply current	V_{CC} = 5.5V; V_{I} = GND or V_{CC}		2	50		50	μA			
ΔI _{CC}	Additional supply current per input pin ²	V_{CC} = 5.5V; One data input at 3.4V, other inputs at V_{CC} or GND		0.25	500		500	μΑ			

NOTES:

1. Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

2. This is the increase in supply current for each input at 3.4V.

3. For valid test results, data must not be loaded into the flip-flop or latch after applying the power.

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AC CHARACTERISTICS

GND = 0V; $t_R = t_F = 2.5$ ns; $C_L = 50$ pF, $R_L = 500\Omega$

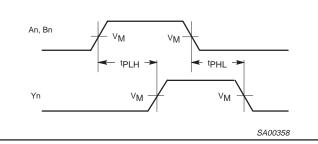
					LIMIT	s		
SYMBOL	PARAMETER	WAVEFORM	T _a V	_{mb} = +25° _{CC} = +5.0	C V	$T_{amb} = -40^{\circ}$ $V_{CC} = +5$	°C to +85°C .0V ±0.5V	UNIT
			MIN	TYP	MAX	MIN	MAX	
t _{PLH} t _{PHL}	Propagation delay An, Bn to Yn	1	1.0 1.0	2.3 1.9	3.4 2.9	1.0 1.0	3.8 3.2	ns
^t OSHL ^t OSLH ¹	Output to Output skew An or Bn to $\overline{Y}n$			0.4	0.5		0.5	ns

NOTE:

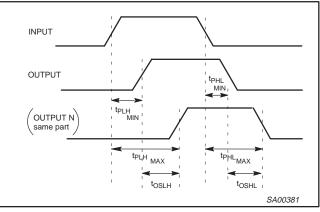
 Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the the same direction, either HIGH–to-LOW (t_{OSHL}) or LOW-to-HIGH (t_{OSLH}); parameter guaranteed by design.

AC WAVEFORMS

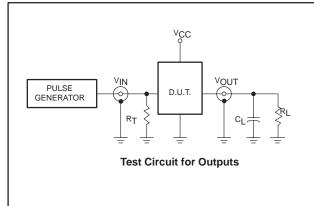
 $V_{M} = 1.5V, V_{IN} = GND \text{ to } 3.0V$



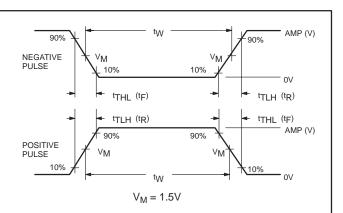
Waveform 1. Propagation delay for inverting outputs



Waveform 2. Common edge skew



TEST CIRCUIT AND WAVEFORMS



Input Pulse Definition

DEFINITIONS

- R_L = Load resistor; see AC CHARACTERISTICS for value.
- $\begin{array}{ll} C_L = & Load \mbox{ capacitance includes jig and probe capacitance;} \\ & see \mbox{ AC CHARACTERISTICS for value.} \end{array}$
- $\label{eq:RT} \textbf{R}_{T} = \quad \text{Termination resistance should be equal to } \textbf{Z}_{OUT} \text{ of } \\ \text{pulse generators.}$

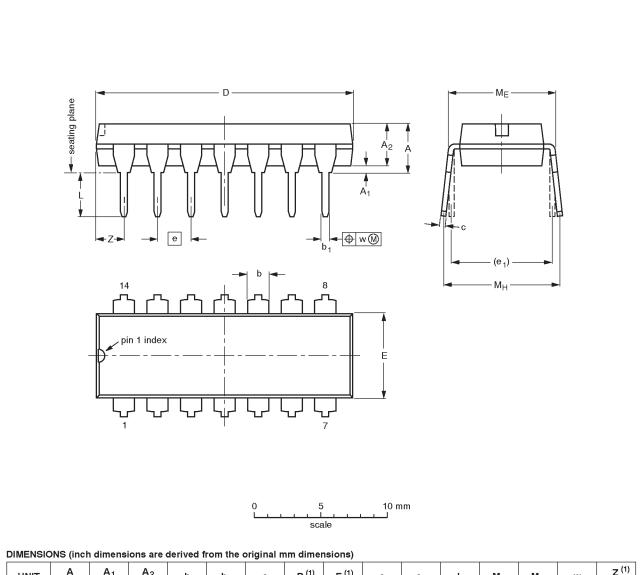
	IN	PUT PULSE R	EQUIRE	MENTS	
FAMILY	Amplitude	Rep. Rate	t _W	t _R	t _F
74ABT	3.0V	1MHz	500ns	2.5ns	2.5ns
					SH00067

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Quad 2-input OR gate

DIP14: plastic dual in-line package; 14 leads (300 mil)



U	NIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	c	D ⁽¹⁾	E ⁽¹⁾	e	e ₁	L	ME	M _H	w	Z ⁽¹⁾ max.
r	nm	4.2	0.51	3.2	1.73 1.13	0.53 0.38	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.2
in	ches	0.17	0.020	0.13	0.068 0.044	0.021 0.015	0.014 0.009	0.77 0.73	0.26 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.087

Note

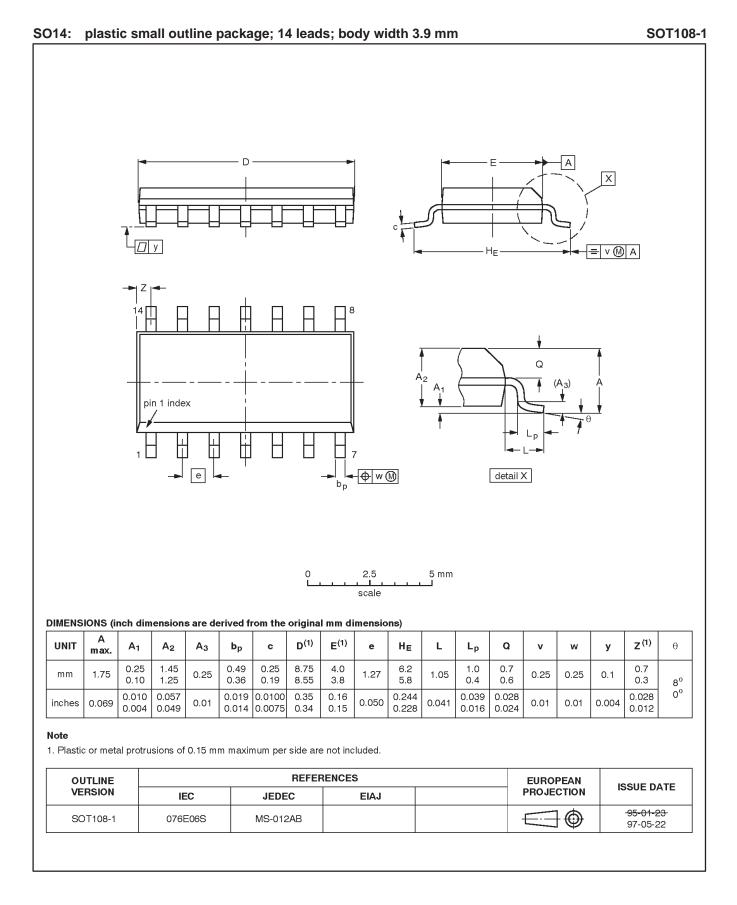
1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE	REFERENCES				EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT27-1	050G04	MO-001AA				-92-11-17 95-03-11

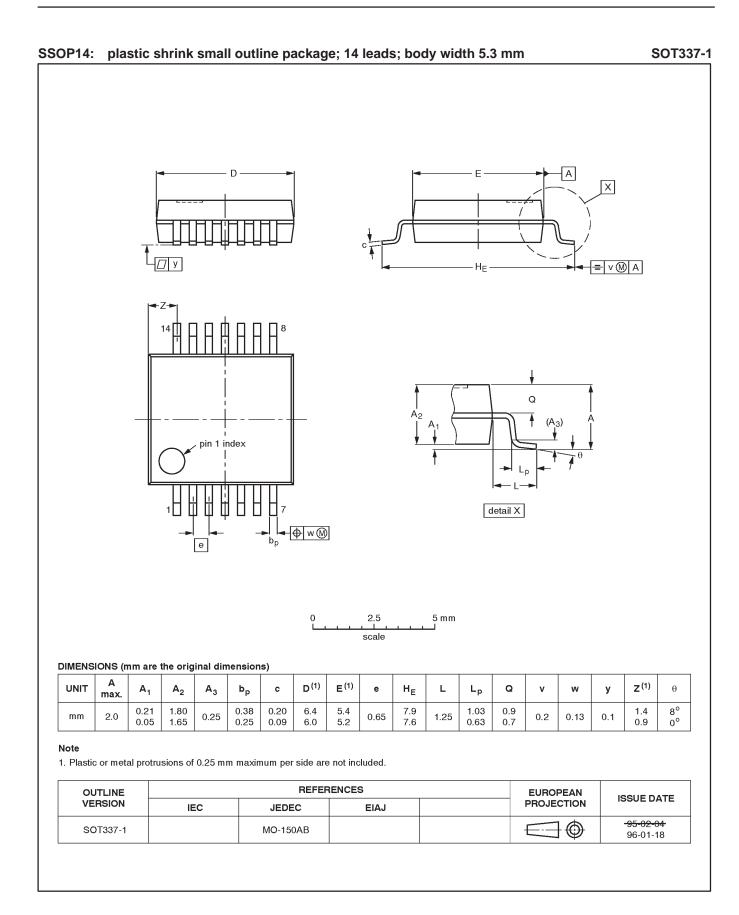
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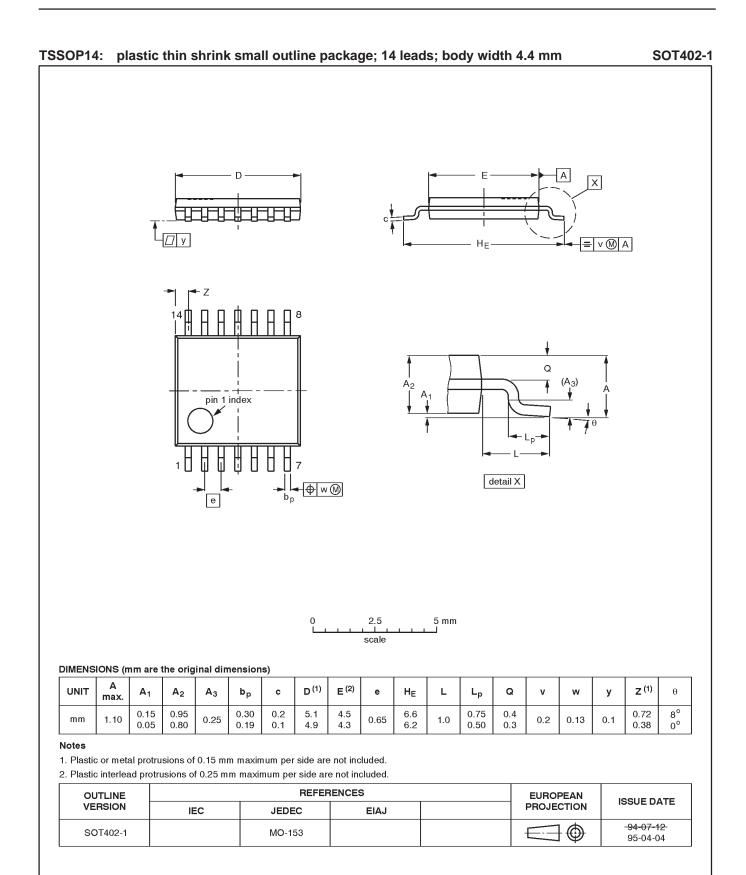
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NOTES

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DEFINITIONS						
Data Sheet Identification	Product Status	Definition				
Objective Specification	Formative or in Design	This data sheet contains the design target or goal specifications for product development. Specifications may change in any manner without notice.				
Preliminary Specification	Preproduction Product	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.				
Product Specification	Full Production	This data sheet contains Final Specifications. Philips Semiconductors reserves the right to make changes at any time without notice, in order to improve design and supply the best possible product.				

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